

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/605,650	CHANG, YEN-JEN
	Examiner	Art Unit
	Brian E. Miller	2627

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
720	698, 692	1/17/2007	BEM
720	611	1/17/2007	BEM
EAST PGPUB (interference) search		1/17/2007	BEM

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Search	10/12/2006	BEM
PLUS Search	10/13/2006	BEM
EAST updated Search (enclosed)	1/17/2007	BEM